Search Notes							

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Applicant(s)/Patent under Reexamination

YAMAKAWA ET AL.

10/809,340

Examiner

Art Unit

CUONG H. NGUYEN

3661

SEARCHED					
Class	Subclass	Date	Examiner		
701	1,21	5/17/2007	CHN		
318	580,588	5/17/2007	CHN		
114	144R	5/17/2007	CHN		
	:				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
WEST/DERWENT	5/18/2007	CHN
Inventors'names search	5/18/2007	CHN
IEEE Xplore	5/26/2007	CHN
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